Product data sheet

1. General description

Planar passivated AC Thyristor Triac power switch in a TO220F "full pack" plastic package with self-protective capabilities against low and high energy transients.

2. Features and benefits

- · Clamping structure ensuring safe high over-voltage withstand capability
- · Direct interfacing with low power drivers and microcontrollers
- Full cycle AC conduction
- Over-voltage withstand capability to IEC 61000-4-5
- · Pin compatible with standard triacs
- Planar passivated for voltage ruggedness and reliability
- Safe clamping capability for low energy over-voltage transients
- Self-protective turn-on during high energy voltage transients
- · Sensitive gate for easy logic level triggering
- · Very high immunity to false turn-on by dV/dt
- RoHS compliant
- Halogen free for DG version
- · Epoxy package meets UL94V-0 which guaranteed by epoxy molding compound
- Isolated package (V_{iso} = 2500 V_{RMS})

3. Applications

- AC fan, pump and compressor controls
- · Highly inductive, resistive and safety loads
- · Large and small appliances (White Goods)
- · Reversing induction motor controls

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	-	800	V
I _{T(RMS)}	RMS on-state current	full sine wave; $T_h \le 81 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3	-	-	6	А
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig. 4; Fig. 5	-	-	56	Α
		full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 16.7 \text{ ms}$	-	-	51	Α
T _j	junction temperature		-	-	125	°C
V_{PP}	peak pulse voltage	T _j = 25 °C; non-repetitive, off-state; Fig. 6	-	-	2	kV
Static ch	aracteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G+;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	10	mA

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 10</u>	-	-	25	mA
V _T	on-state voltage	I _τ = 8 A; T _j = 25 °C; <u>Fig. 11</u>	-	-	1.7	V
V _{CL}	clamping voltage	$I_{CL} = 0.1 \text{ mA; } t_p = 1 \text{ ms; } T_j = 25 \text{ °C}$	850	-	-	V
Dynamic	characteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 13	500	-	-	V/µs
dI _{com} /dt	rate of change of commutating current	$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 6 \text{ A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; \text{ gate open circuit};$ Fig. 14; Fig. 15	3.5	-	-	A/ms

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	CM	common	mb	1.0
2	LD	load		LD
3	G	gate		G
mb	n.c.	mounting base; isolated		CM 003aaf296

6. Ordering information

Table 3. Ordering information

Table 6. Grading information							
Type number	Package	Orderable part number	Packing	Small packing	Package	Package	
	Name		method	quantity	version	issue date	
ACTT6X-800E	TO220F	ACTT6X-800E,127	Tube	50	SOT186A	14-Nov-2013	
ACTT6X-800E/DG	TO220F	ACTT6X-800E/DGQ	Tube	50	SOT186A	14-Nov-2013	

7. Marking

Table 4. Marking codes

Type number	Marking codes			
	Assembly factory: d	Assembly factory: A		
ACTT6X-800E	ACTT6X 800E PJdxxxx xx	ACTT6X 800E PJAxxxx xx		
ACTT6X-800E/DG	N/A	ACTT6X 800EDG PJAxxxx xx		

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Mii	n Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	800	V
I _{T(RMS)}	RMS on-state current	full sine wave; $T_h \le 81 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3	-	6	A
I _{TSM}	non-repetitive peak on-state current	full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig 4; Fig 5	-	56	А
		full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 16.7 \text{ ms}$	-	51	Α
I ² t	I ² t for fusing	t _p = 10 ms; sine-wave pulse	-	13	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 20 mA	-	100	A/µs
I _{GM}	peak gate current	t _p = 20 μs	-	2	А
P_{GM}	peak gate power		-	5	W
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.5	W
T _j	junction temperature		-	125	°C
V_{pp}	peak pulse voltage	T _j = 25 °C; non-repetitive, off-state; Fig 6	-	2	kV

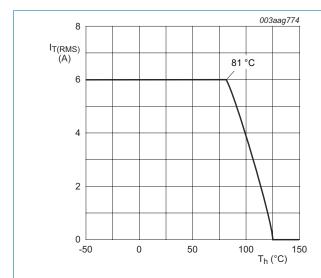
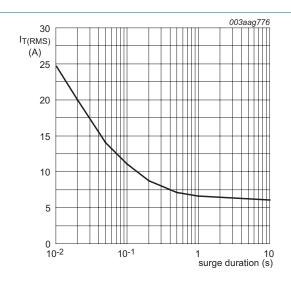
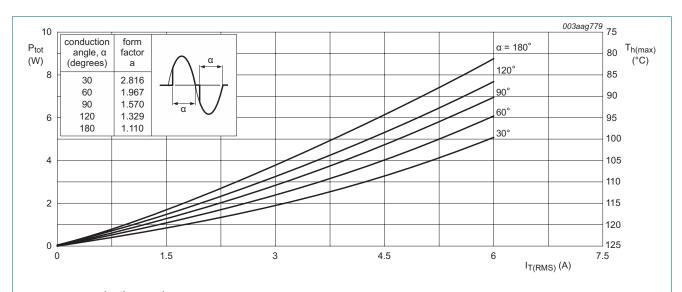


Fig. 1. RMS on-state current as a function of heatsink temperature; maximum values



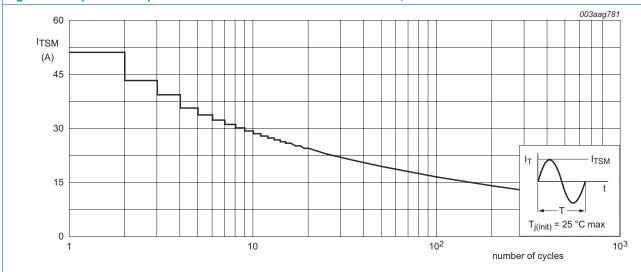
f = 50 Hz; T_h = 81 °C Fig. 2. RMS on-state current as a function of surge duration; maximum values



 α = conduction angle

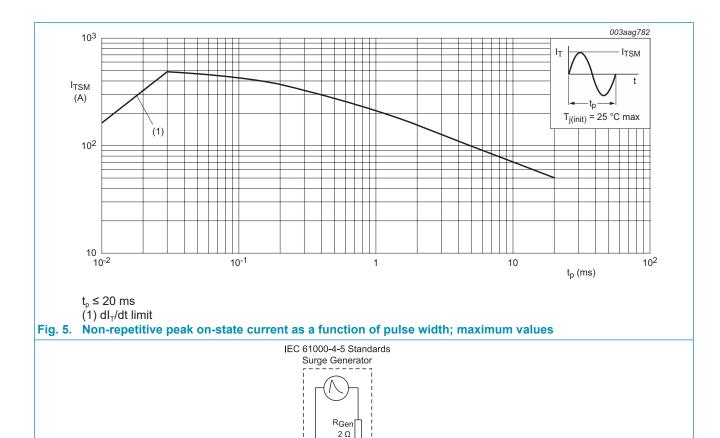
 $a = form factor = I_{T(RMS)} / I_{T(AV)}$

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



R

18 Ω

Load Model

2 µH ¦

Rg

------220 Ω

003aak842

Fig. 6. Test circuit for inductive and resistive loads with conditions equivalent to IEC 61000-4-5

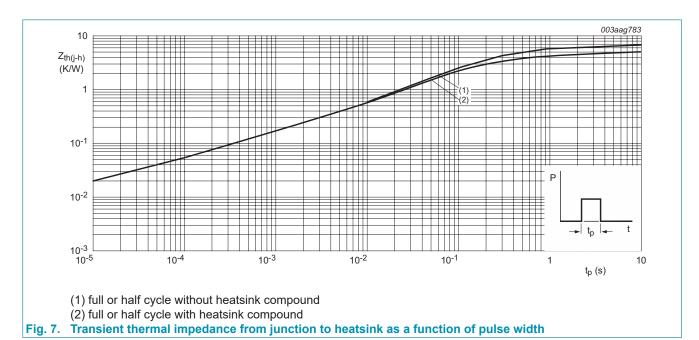
Filtering Unit

AC Mains

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-h)}	thermal resistance from junction to heatsink	full or half cycle with heatsink compound; Fig. 7	-	-	5	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient free air	in free air	-	55	-	K/W



10. Isolation characteristics

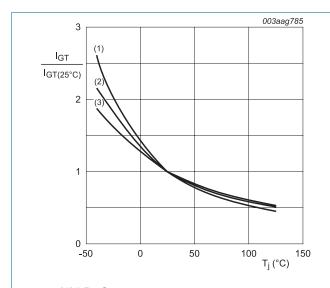
Table 7. Isolation characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{isol(RMS)}	RMS isolation voltage	sinusoidal waveform; from all pins to external heatsink; clean and dust free; 50 Hz \leq f \leq 60 Hz; RH \leq 65 %; T _h = 25 °C	-	-	2500	V
C _{isol}	isolation capacitance	from LD pin to external heatsink; f = 1 MHz; T_h = 25 °C	-	10	-	pF

11. Characteristics

Table 8. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G+;}$ $T_j = 25 \text{ °C; Fig. 8}$	-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G-;}$ $T_j = 25 \text{ °C; Fig. 8}$	-	-	10	mA
		$V_D = 12 \text{ V}; I_T = 100 \text{ mA}; LD- G-; $ $T_j = 25 \text{ °C}; Fig. 8$	-	-	10	mA
IL	latching current	$V_D = 12 \text{ V}; I_G = 100 \text{ mA}; \text{LD+ G+};$ $T_j = 25 ^{\circ}\text{C}; Fig. 9$	-	-	30	mA
		$V_D = 12 \text{ V}; I_G = 100 \text{ mA}; \text{LD+ G-};$ $T_j = 25 \text{ °C}; Fig. 9$	-	-	40	mA
		$V_D = 12 \text{ V; } I_G = 100 \text{ mA; LD- G-;}$ $T_j = 25 \text{ °C; } Fig. 9$	-	-	30	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 10</u>	-	-	25	mA
V _T	on-state voltage	I _T = 8 A; T _j = 25 °C; <u>Fig. 11</u>	-	-	1.7	V
V _{GT} gate tri	gate trigger voltage	$V_D = 12V; I_T = 100 \text{ mA}; T_j = 25 \text{ °C};$ Fig. 12	-	0.8	1	V
		V _D = 400V; I _T = 100 mA;T _j = 125 °C	0.2	0.45	-	V
I _D	off-state current	V _D = 800 V; T _j = 25 °C	-	-	10	μA
		V _D = 800 V; T _j = 125 °C	-	-	0.5	mA
V _{CL}	clamping voltage	$I_{CL} = 0.1 \text{ mA}; t_p = 1 \text{ ms}; T_j = 25 \text{ °C}$	850	-	-	V
Dynamic	characteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 13	500	-	-	V/µs
dl _{com} /dt	rate of change of commutating current	V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 6 A; dV_{com}/dt = 20 V/ μ s; gate open circuit; Fig. 14; Fig. 15	3.5	-	-	A/ms
		V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 6 A; dV_{com}/dt = 10 V/ μ s; gate open circuit; Fig. 14; Fig. 15	5	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 6 \text{ A};$ $dV_{com}/dt = 1 \text{ V}/\mu\text{s}; \text{ gate open circuit};$ Fig. 14; Fig. 15	10	-	-	A/ms



- (1) LD- G-
- (2) LD+ G+
- (3) LD+ G-

Fig. 8. Normalized gate trigger current as a function of junction temperature

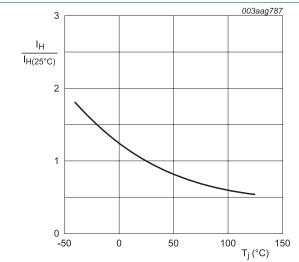


Fig. 10. Normalized holding current as a function of junction temperature

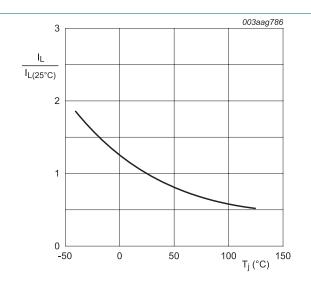
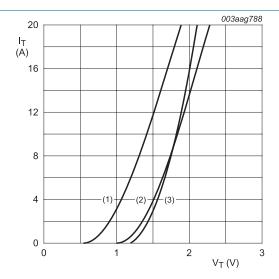


Fig. 9. Normalized latching current as a function of junction temperature



 $V_o = 1.109 \text{ V}; R_s = 0.076 \Omega$

(1) T_j = 125 °C; typical values (2) T_j = 125 °C; maximum values

(3) $T_i = 25$ °C; maximum values

Fig. 11. On-state current as a function of on-state voltage

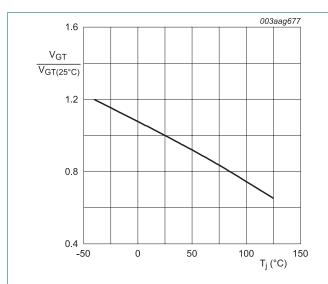
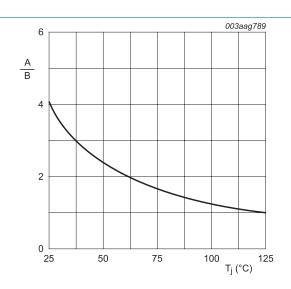
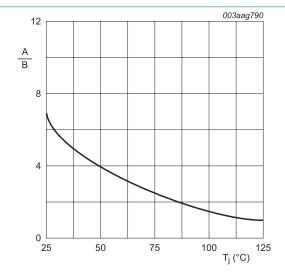


Fig. 12. Normalized gate trigger voltage as a function of junction temperature



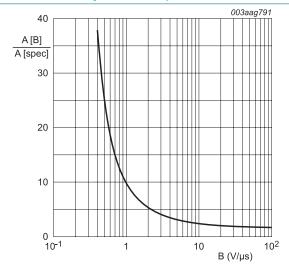
A = dV_D/dt at condition T_j °C B = dV_D/dt at condition T_j [125] °C

Fig. 13. Normalized rate of rise of off-state voltage as a function of junction temperature



A = dI_{com}/dt at condition T_j °C B = dI_{com}/dt at condition T_j [125] °C V_D = 400 V

Fig. 14. Normalized critical rate of rise of commutating current as a function of junction temperature

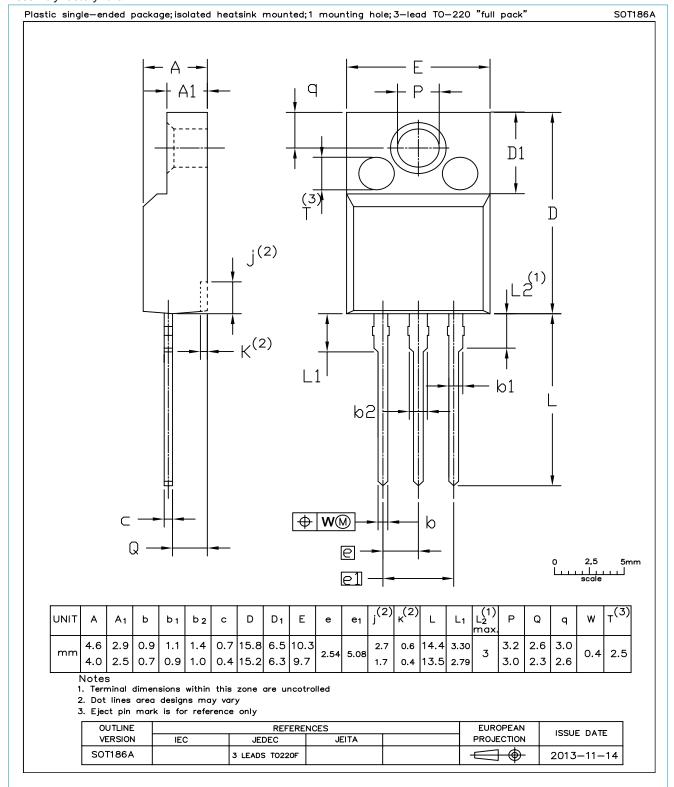


A [B] = dI_{com}/dt at condition B, dV_{com}/dt A [spec] is the specified data sheet value for dI_{com}/dt turn-off time < 20 ms

Fig. 15. Normalized critical rate of change of commutating current as a function of critical rate of change of commutating voltage; minimum values

12. Package outline

Assembly factory: d & A



13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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